

# PATENT ABSTRACTS OF JAPAN

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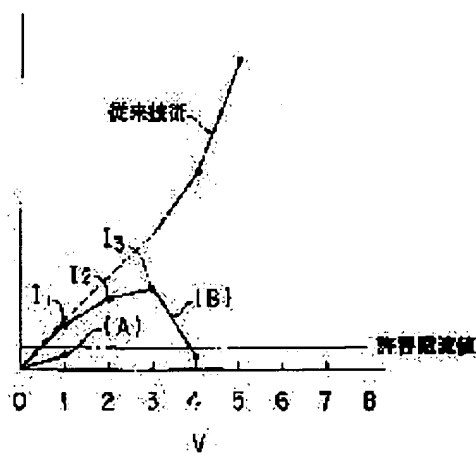
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## (54) METHOD FOR ELIMINATING SHORT-CIRCUITED PART OF SOLAR CELL

### (57)Abstract:

**PROBLEM TO BE SOLVED:** To provide a method for surely eliminating short-circuited parts generated in a thin-film solar cell, while preventing the condition of the short-circuited parts from degrading rather than better by application of voltage in the reverse direction.

**SOLUTION:** Leak current is measured, while voltage in a reverse direction having a prescribed value is applied to both provide and negative electrodes of a solar cell and the reverse-biasing process is finished, when the leak current has reached the permissible value or smaller. Also, a leakage current I1 is measured, while voltage in reverse direction having a specified voltage value is applied and a leakage current I2 is measured while voltage in the reverse direction having a higher voltage value than the previous voltage value is applied, when the leakage current I1 exceeds the permissible value. Leakage current is measured, while voltage in the reverse direction having a still voltage value is applied, when the leak current I2 does not show tendency to increase. The reverse-biasing and measuring operation is repeated and is finished, when the leakage current I2 shows the tendency to increase.



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